S arch Notes		

Applicati n N .	Applicant(s)
09/588,195	OZZIE ET AL.
Examiner	Art Unit
Maikhanh Nguyen	2176

SEARCHED				
Class	Subclass	Date	Examiner	
Updated	Search	1/18/2005	MK	
715	513	1/21/2005	мк	
	530	1/21/2005	МК	
	501.1	1/21/2005	МК	
709	201	1/21/2005	MK	
	206	1/21/2005	мк	
	215	1/21/2005	мк	
711	147	1/21/2005	МК	
	202	1/21/2005	мк	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
715	513	1/21/2005	MK		
	530	1/21/2005	МК		
711	202	1/21/2005	МК		
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SEARCH N (INCLUDING SEARC)
	DATE	EXMR
West Search	1/18/2005	MK
Consulted with Joseph Feild	1/18/2005	MK
West Search	1/21/2005	MK
NPL (IEEE)	1/21/2005	MK